

Notice of References Cited	Application/Control No. 10/578,988		Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
	Examiner Jennifer Dieterle		Art Unit 1795	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	Examiner Jennifer Dieterle	Art Unit 1795	Page 1 of 1

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